

# **FuTuRe 2019 - Workshop on the Future of Silicon Detector Technologies**

## **Report of Contributions**

Contribution ID: 1

Type: **not specified**

## Arrival and Registration

*Monday, December 2, 2019 8:30 AM (30 minutes)*

Contribution ID: 2

Type: **not specified**

## Welcome address

*Monday, December 2, 2019 9:00 AM (10 minutes)*

**Presenter:** Prof. ORTLEPP, Thomas (CiS)

Contribution ID: 3

Type: **not specified**

## Coffee Break

Contribution ID: 4

Type: **not specified**

## Lunch Break

Contribution ID: 5

Type: **not specified**

## Coffee Break

Contribution ID: 6

Type: **not specified**

## Coffee Break

Contribution ID: 7

Type: **not specified**

## Workshop Dinner



Contribution ID: 8

Type: **not specified**

## Lunch Break

Contribution ID: 9

Type: **not specified**

## Coffee Break

Contribution ID: **10**

Type: **not specified**

## **End of the workshop**

*Tuesday, December 3, 2019 4:30 PM (30 minutes)*

Contribution ID: **11**

Type: **not specified**

## **Arrival and Registration**

*Tuesday, December 3, 2019 8:30 AM (30 minutes)*

Contribution ID: 12

Type: **not specified**

## **Introduction of SiDE Business Unit of CiS**

*Monday, December 2, 2019 9:10 AM (30 minutes)*

**Presenter:** RODER, Ralf Mario (CIS Institut fuer Mikrosensorik GmbH (DE))

Contribution ID: 13

Type: **not specified**

**tbd**

*Monday, December 2, 2019 9:40 AM (30 minutes)*

**Presenter:** Prof. YOSHIKAWA, Nobuyuki (Yokohama National University)

**Session Classification:** Readout Electronics

Contribution ID: 14

Type: **not specified**

**tbd**

*Monday, December 2, 2019 10:10 AM (30 minutes)*

**Presenter:** Mr HIRONAKA, Yoshi (Yokohama National University)

**Session Classification:** Readout Electronics

Contribution ID: 15

Type: **not specified**

## **Superconducting NbN Hot-Electron Bolometer as a Fast Diagnostic Tool for Accelerator Light Sources: System and Readout Design**

*Monday, December 2, 2019 11:15 AM (30 minutes)*

**Presenter:** Mr SCHMID, Alexander (Karlsruhe Institut für Technologie)

**Session Classification:** Readout Electronics



Contribution ID: **16**

Type: **not specified**

**tbd**

*Monday, December 2, 2019 11:45 AM (30 minutes)*

**Presenter:** Prof. ORTLEPP, Thomas (CiS)

**Session Classification:** Readout Electronics

Contribution ID: 17

Type: **not specified**

## **Introduction to Processes and Workflow in Radiation Oncology**

*Monday, December 2, 2019 1:30 PM (30 minutes)*

**Presenter:** Mr SCHILZ, Johannes (Strahlenschutzseminar in Thüringen e.V.)

**Session Classification:** Dosimetry in Radiation Therapy

Contribution ID: **18**

Type: **not specified**

**tbd**

*Monday, December 2, 2019 2:00 PM (30 minutes)*

**Presenter:** Mr KRANZER, Rafael (PTW Freiburg)

**Session Classification:** Dosimetry in Radiation Therapy

Contribution ID: **19**

Type: **not specified**

**tbd**

*Monday, December 2, 2019 2:30 PM (30 minutes)*

**Presenter:** Mrs SCHADE, Stephanie (Technische Hochschule Mittelhessen)

**Session Classification:** Dosimetry in Radiation Therapy

Contribution ID: 20

Type: **not specified**

## **Semiconductor-based detectors for dosimetry in radiation therapy**

*Monday, December 2, 2019 3:30 PM (30 minutes)*

**Presenter:** Prof. KRAUTSCHNEIDER, Wolfgang (TU Hamburg)

**Session Classification:** Dosimetry in Radiation Therapy

Contribution ID: 21

Type: **not specified**

## **From detectors for proton cancer therapy to atomic defect characterizations with positrons**

*Monday, December 2, 2019 4:00 PM (30 minutes)*

**Presenter:** Dr WAGNER, Andreas (HZDR Nuclear Physics Division)

**Session Classification:** Dosimetry in Radiation Therapy

Contribution ID: 22

Type: **not specified**

## **Detector Development for Photon Science at PSI**

*Tuesday, December 3, 2019 9:00 AM (30 minutes)*

**Presenter:** SCHMITT, Bernd (Paul Scherrer Institut)

**Session Classification:** Sensor Development for X-Rays

Contribution ID: 23

Type: **not specified**

## **Towards soft X-ray detection using LGAD sensors**

*Tuesday, December 3, 2019 9:30 AM (30 minutes)*

**Presenter:** ZHANG, Jiaguo (Paul Scherrer Institut)

**Session Classification:** Sensor Development for X-Rays



Contribution ID: 24

Type: **not specified**

**tbd**

*Tuesday, December 3, 2019 10:30 AM (30 minutes)*

**Presenter:** CORREA MAGDALENA, Jonathan (Deutsches Elektronen-Synchrotron DESY)

**Session Classification:** Sensor Development for X-Rays

Contribution ID: 25

Type: **not specified**

## Doping Profiles for Shallow Junctions

*Tuesday, December 3, 2019 11:00 AM (30 minutes)*

**Presenter:** WITTIG, Tobias (CIS Institut fuer Mikrosensorik GmbH (DE))

**Session Classification:** Sensor Development for X-Rays

Contribution ID: 26

Type: **not specified**

## Discussion

*Tuesday, December 3, 2019 11:30 AM (30 minutes)*

**Session Classification:** Sensor Development for X-Rays

Contribution ID: 27

Type: **not specified**

## **Density Functional Theory-based theory of defects**

*Tuesday, December 3, 2019 1:00 PM (30 minutes)*

**Presenter:** Prof. RUNGE, Erich (Technische Universität Ilmenau)

**Session Classification:** Defect Engineering

Contribution ID: 28

Type: **not specified**

## **Development of Radiation Hard Silicon Detectors - The RD50 collaboration**

*Tuesday, December 3, 2019 1:30 PM (30 minutes)*

**Presenter:** MOLL, Michael (CERN)

**Session Classification:** Defect Engineering

Contribution ID: 29

Type: **not specified**

## **Light-induced defects in silicon solar cells: a possible impact on the mainstream silicon technology**

*Tuesday, December 3, 2019 2:00 PM (30 minutes)*

**Presenter:** Mr MCHEDLIDZE, Teimuraz (TU Dresden)

**Session Classification:** Defect Engineering

Contribution ID: 30

Type: **not specified**

## Defects in 6" Cz Si EPI-wafer

*Tuesday, December 3, 2019 3:00 PM (30 minutes)*

**Presenter:** Mrs SEIFERT, Daniela (X-FAB Semiconductor Foundries GmbH)

**Session Classification:** Defect Engineering

Contribution ID: 31

Type: **not specified**

## **Low gain avalanche detectors (LGAD) –Can the A\_Si-Si\_i defect explain their insufficient radiation hardness?**

*Tuesday, December 3, 2019 3:30 PM (30 minutes)*

**Presenter:** LAUER, Kevin (CIS Institut fuer Mikrosensorik GmbH (DE))

**Session Classification:** Defect Engineering



Contribution ID: 32

Type: **not specified**

## Discussion

*Tuesday, December 3, 2019 4:00 PM (30 minutes)*

**Session Classification:** Defect Engineering